**SDLS103** 

DECEMBER 1983-REVISED MARCH 1988

 Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs

 Dependable Texas Instruments Quality and Reliability

#### description

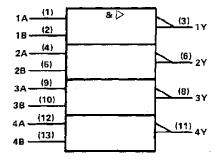
These devices contain four independent 2-input NAND buffer gates.

The SN5437, SN54LS37 and SN54S37 are characterized for operation over the full military range of  $-55\,^{\circ}\text{C}$  to  $125\,^{\circ}\text{C}$ . The SN7437, SN74LS37 and SN74S37 are characterized for operation from  $0\,^{\circ}\text{C}$  to  $70\,^{\circ}\text{C}$ .

#### FUNCTION TABLE (each gate)

	INP	UTS	OUTPUT
	Α	В	Y
	Н	Н	L
-	L	×	н
	х	L	н

## logic symbol†



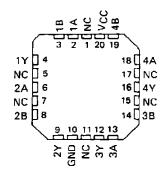
 $<sup>^\</sup>dagger$  This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

SN5437, SN54LS37, SN54S37 . . . J OR W PACKAGE SN7437 . . . N PACKAGE SN74LS37, SN74S37 . . . D OR N PACKAGE (TOP VIEW)

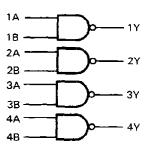
1А ЏТ	U14DVCC
1В □2	13 <b>□</b> 48
17 □3	12 AA
2A 🗆 4	11 4Y
28 □5	10 <b>□</b> 3B
2Y 🛮 6	9∐3A
GND 🗖 7	8 <b>□</b> 3 Y

SN54LS37, SN54S37 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

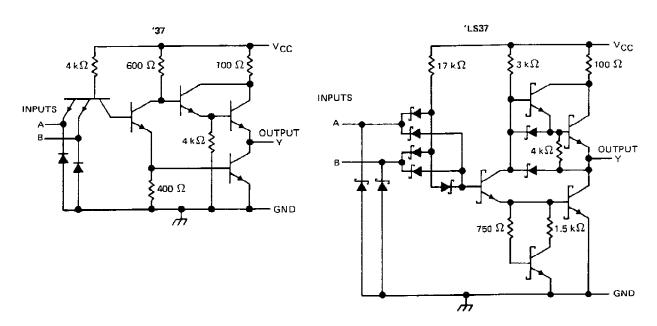
### logic diagram

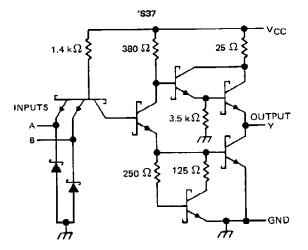


# positive logic

 $Y = \overline{A \cdot B}$  or  $Y = \overline{A} + \overline{B}$ 

# schematics (each gate)





Resistor values shown are nominal.

# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, Voc (see Note 1	]] ,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	7 V
1 \$37		7 V
Onerating free-air temperature:	### Company Co	. –55°C to 125°C
	SN74'	0°C to 70°C
Storage temperature range		. –65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



# recommended operating conditions

		SN5437			SN7437			
	MIN	NOM	MAX	MIN	MOM	MAX	UNIT	
V <sub>CC</sub> Supply voltage	4.5	5	5.5	4.75	5	5.25	V	
VIH High-level input voltage	2			2			V	
VIL Low-level input voltage			8.0			0.8	V	
IOH High-level output current			- 1.2			- 1.2	mΑ	
IOL Low-level output current			48			48	mΑ	
TA Operating free-air temperature	- 55		125	0		70	°C	

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS †		T	SN5437		T	UNIT		
PARAMETER				MIN	TYP ‡	MAX	MIN	TYP#	MAX	UNII
Vik	V <sub>CC</sub> ≈ MIN,	I <sub>I</sub> = - 12 mA				- 1.5			- 1.5	V
v <sub>он</sub>	V <sub>CC</sub> = MIN.	V <sub>IL</sub> = 0.8 V,	I <sub>QH</sub> = - 1.2 mA	2.4	3.3		2.4	3.3		V
Vol	V <sub>CC</sub> ≈ MIN,	V <sub>IH</sub> = 2 V,	lot = 48 mA		0.2	0.4		0.2	0.4	V
T <sub>1</sub>	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 6.5 V				1			1	mA
ЧH	V <sub>CC</sub> = MAX,	V <sub> </sub> = 2.4 V				40			40	μА
հլը	VCC = MAX,	V <sub>I</sub> = 0.4 V				- 1.6			- 1.6	mA
Ios §	V <sub>CC</sub> = MAX			- 20		- 70	- 18		- 70	mA
Гссн	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 0 V			9	15.5		9	15.5	mΑ
ICCL	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 4.5 V			34	54		34	54	mA

# switching characteristics, $V_{CC}$ = 5 V, $T_A$ = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CON	MIN T	ΓΥΡ	MAX	UNIT	
tPLH	A or B	v	P 122 D	C: - 45 pC		13	22	กร
<sup>†</sup> PHL	A Or B	Y	R <sub>L</sub> = 133 Ω, C <sub>L</sub> = 45 pF			8	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. ‡ All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_{A} = 25^{\circ}\text{C}$ . § Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

# SN54LS37, SN74LS37 **QUADRUPLE 2-INPUT POSITIVE-NAND BUFFERS**

#### recommended operating conditions

		8	SN54LS37			SN74LS37			
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	V	
VIH	High-level input voltage	2			2			V	
VIL	Low-level input voltage			0.7			8.0	V	
Iон	High-level output current			<b>- 1.2</b>			-1.2	mA	
loL	Low-level output current			12		_	24	mA	
TA	Operating free-air temperature	- 55		125	0		70	°c	

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †		8	N54LS	37	8	37	UNIT		
PARAMETER	125. 65/15/11/5/6			MIN	TYP‡	MAX	MIN	TYP#	MAX	UNIT
VIK	V <sub>CC</sub> - MIN,	4 <sub>1</sub> 18 mA				- 1.5			- 1.5	V
Voн	VCC = MIN,	V <sub>IL</sub> = MAX,	I <sub>OH</sub> = − 1.2 mA	2.5	3.4		2.7	3.4		V
Va.	VCC = MIN,	V <sub>IH</sub> = 2 V,	OL = 12 mA		0.25	0.4		0.25	0.4	٧
VoL	VCC = MIN,	V <sub>JH</sub> = 2 V,	1 <sub>OL</sub> = 24 mA					0.35	0.5	
l <sub>l</sub>	V <sub>CC</sub> = MAX,	V <sub>I</sub> = 7 V				0.1			0.1	mΑ
IJН	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 2.7 V				20			20	μΑ
i L	V <sub>CC</sub> = MAX,	V <sub>I</sub> = 0.4 V				- 0.4			- 0.4	mA
105 §	V <sub>CC</sub> = MAX			- 30		130	- 30		- 130	mΑ
ГССН	VCC = MAX,	V <sub>1</sub> = 0 V			0.9	2		0.9	2	mA
ICCL	V <sub>CC</sub> = MAX,	V <sub>I</sub> = 4.5 V			6	12		6	12	mΑ

# switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CON	DITIONS	MIN TYP	MAX	UNIT
tPLH	Λ - ν - Π	v	$R_1 = 667 \Omega_s$	C. + AE nC	12	24	ns
<sup>t</sup> PHL	A or B	Ţ	$R_L = 667 \Omega$ , $C_L = 45 pF$	12	24	ns	

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. ‡ All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ . § Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

# SN54S37, SN74S37 QUADRUPLE 2-INPUT POSITIVE-NAND BUFFERS

# recommended operating conditions

			SN54S37			SN74S37			
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vcc	Supply voltage	4.5	5	5.5	4.75	- 5	5.25	V	
VIH	High-level input voltage	2			2	•		V	
VIL	Low-level input voltage			8.0			8.0	V	
ЮН	High-level output current			<b>–</b> 3			- 3	mA	
IOL	Low-level output current			60			60	mΑ	
TA	Operating free-air temperature	- 55		125	0		70	°C	

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST CONDITIONS T	SN54S37	SN74S37
PARAMETER	TEST CONDITIONS T	MIN TYP\$ MAX	MIN TYP MAX
VIK	V <sub>CC</sub> = MIN, I <sub>1</sub> = - 18 mA	-1.2	– 1.2 \
Voн	V <sub>CC</sub> = MIN, V <sub>IL</sub> = 0.8 V, I <sub>OH</sub> = - 3 mA	2.5 3.4	2.7 3.4
VOL	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, I <sub>OL</sub> = 60 mA	0.5	0.5 \
l <sub>1</sub>	VCC = MAX, VI = 5.5 V	1	1 m
ПН	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7 V	0.1	0.1 m
IIL I	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.5 V	-4	-4 m
Ios§	V <sub>CC</sub> = MAX	- 50 - 225	−50 −225 m
ГССН	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0 V	20 36	20 36 m
CCL	V <sub>CC</sub> = MAX, V <sub>I</sub> = 4.5	46 80	46 80 m

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

# switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CON	NOITIONS	MIN TYP	MAX	UNIT
tPLH		ar B	R <sub>L</sub> = 93 Ω,	C <sub>L</sub> = 50 pF	4	6.5	ns
tPHL	A or B				4	6.5	ns
tPLH	A Or B		R <sub>L</sub> = 93 Ω,	C <sub>L</sub> = 150 pF	6		กร
<sup>†</sup> PHL		<u> </u>			6		ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

<sup>\$</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed 100 milliseconds.

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